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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
PATENT APPLICATION

Applicant: Bazan et al. Serial No.: 10/710640
Filed: 07/24/2004 Atty. Docket: BUR920040044US1
Title: CIRCUIT AND METHOD FOR MONITORING DEFECTS.

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR 1.56, 1.97, 1.98

Honorable Commissioner of Patents and Trademarks
Washington, D. C. 20231

Sir:

Applicants submit herewith form PTO-1449, listing patents, publications, or other information of which they are aware which they believe may be material to patentability pursuant to 37 CFR 1.56(b), and in respect of which there may be a duty to disclose under 37 CFR 1.56(a), together with legible copies of the patents, publications, or other information listed.

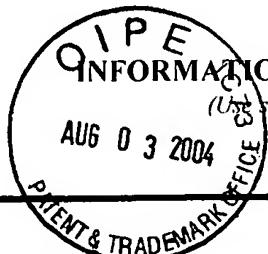
While the items submitted with this Information Disclosure Statement may be material to patentability pursuant to 37 CFR 1.56, in accordance with 37 CFR 1.97(h) it shall not be construed to be an admission that any patent, publication, or other information cited is "prior art" or is material to patentability for this invention unless specifically designated as such. In accordance with 37 CFR 1.97(g), the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made or that no other information material to patentability, as defined in 37 CFR 1.56(b), exists.

Respectfully submitted,

Date: 7/30/04

By:

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INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

Docket Number (Optional)

BUR920040044US1

Application Number

10/710640

Applicant(s)

Bazan et al.

Filing Date

07/24/04

Group Art Unit

U.S. PATENT DOCUMENTS

| *EXAMINER INITIAL | REF | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|-------------------|-----|-----------------|------|------|-------|----------|----------------------------|
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U.S. PATENT APPLICATION PUBLICATIONS

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FOREIGN PATENT DOCUMENTS

| | REF | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | Translation | |
|--|-----|-----------------|--------|---------|-------|----------|-------------|----|
| | | | | | | | YES | NO |
| | | 9027531 | 1/1997 | Japan | | | | |
| | | WO 03/028412 A2 | 4/2003 | PCT | | | | |
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OTHER DOCUMENTS
(Including Author, Title, Date, Pertinent Pages, Etc.)

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| | | Edirisooriya et al., SCAN CHAIN FAULT DIAGNOSIS WITH FAULT DICTIONARIES, 0-7803-2570-2/95 IEEE, pages 1912-1915. |
| | | Edirisooriya et al., DIAGNOSIS OF SCAN PATH FAILURES, 0-818S6-7000-2/95, pages 250-255. |

| EXAMINER | DATE CONSIDERED |
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.